


<b>Search Notes</b>  	<b>Application/Control No.</b>  10533104	<b>Applicant(s)/Patent Under Reexamination</b>  KWEE ET AL.
	<b>Examiner</b>  HONG SANG	<b>Art Unit</b>  1643

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STN database search updated -enclosed	4/17/2008	H.S.
EAST database search updated -enclosed	4/17/2008	H.S.
STIC sequence search -please see search results in SCORE	4/17/2008	H.S.

INTERFERENCE SEARCH			
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